

# OptiMOS<sup>(TM)</sup>3 Power-Transistor

#### **Features**

- · Ideal for high frequency switching
- Optimized technology for DC/DC converters
- Excellent gate charge x R<sub>DS(on)</sub> product (FOM)
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Halogen-free according to IEC61249-2-21

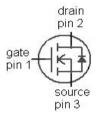
Туре	IPD096N08N3 G
	1 2 (tab)
Package	PG-TO252-3
Marking	096N08N

#### **Product Summary**

V <sub>DS</sub>	80	V
$R_{\mathrm{DS(on),max}}$	9.6	mΩ
I <sub>D</sub>	73	А







## Maximum ratings, at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C <sup>2)</sup>	73	А
		T <sub>C</sub> =100 °C	52	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	292	
Avalanche energy, single pulse <sup>3)</sup>	E <sub>AS</sub>	$I_{\rm D}$ =46 A, $R_{\rm GS}$ =25 $\Omega$	90	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	100	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>2)</sup> See figure 3 for more detailed information

<sup>3)</sup> See figure 13 for more detailed information



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		-	-	1.5	K/W
Thermal resistance,	$R_{thJA}$	minimal footprint	-	-	75	
junction - ambient		6 cm <sup>2</sup> cooling area <sup>4)</sup>	-	-	50	

## **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### **Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	80	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=46~\mu{\rm A}$	2	2.8	3.5	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS} = 80 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.1	1	μΑ
		V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	1	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V <sub>GS</sub> =10 V, I <sub>D</sub> =46 A	-	7.9	9.6	mΩ
		V <sub>GS</sub> =6 V, I <sub>D</sub> =23 A	-	10.5	17.8	
Gate resistance	R <sub>G</sub>		-	1.6	-	Ω
Transconductance	$g_{fs}$	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 46~{\rm A}$	30	60	-	S

 $<sup>^{4)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^2$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol Conditions		Values			Unit	
			min.	typ.	max.		
Dynamic characteristics							
Input capacitance	Ciss		-	1810	2410	рF	
Output capacitance	Coss	$V_{GS}$ =0 V, $V_{DS}$ =40 V, $f$ =1 MHz	-	490	652	]	
Reverse transfer capacitance	C <sub>rss</sub>		-	20	-		
Turn-on delay time	$t_{d(on)}$		-	13	-	ns	
Rise time	t <sub>r</sub>	V <sub>DD</sub> =40 V, V <sub>GS</sub> =10 V,	-	30	-		
Turn-off delay time	$t_{d(off)}$	$I_{D}$ =40 A, $R_{G,ext}$ =1.6 Ω	-	23	-		
Fall time	$t_{\mathrm{f}}$		-	5	-		
Gate Charge Characteristics <sup>5)</sup>		<u> </u>		I .		T _	
Gate to source charge	Q <sub>gs</sub>		-	9	-	nC	
Gate to drain charge	Q <sub>gd</sub>	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =46 A, $V_{\rm GS}$ =0 to 10 V	-	5	-		
Switching charge	$Q_{sw}$		-	10	-		
Gate charge total	Qg		-	26	35		
Gate plateau voltage	$V_{ m plateau}$		-	5.2	-	V	
Output charge	Q <sub>oss</sub>	V <sub>DD</sub> =40 V, V <sub>GS</sub> =0 V	-	35	47	nC	
Reverse Diode							
Diode continous forward current	Is	T -25 °C	-	-	74	А	
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	296		
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =46 A, T <sub>j</sub> =25 °C	-	1.0	1.2	V	
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =40 V, I <sub>F</sub> =40A,	-	57	-	ns	
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/µs	_	91	_	nC	

 $<sup>^{5)}</sup>$  See figure 16 for gate charge parameter definition

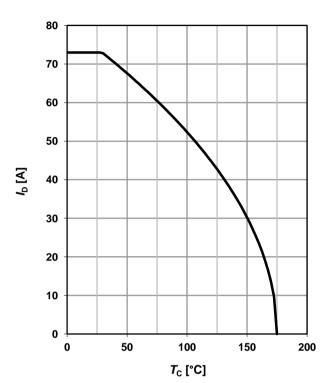


#### 1 Power dissipation

## $P_{\text{tot}} = f(T_{\text{C}})$

# 120 100 80 80 40 20 0 0 50 100 150 200 T<sub>C</sub> [°C]

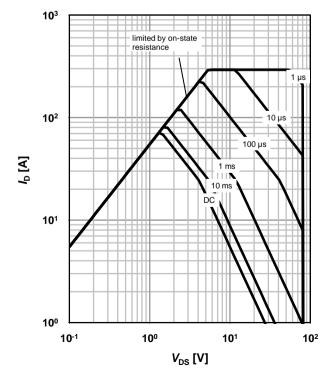
#### 2 Drain current



## 3 Safe operating area

$$I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$$

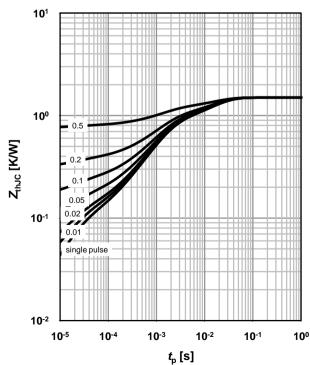
parameter:  $t_p$ 



#### 4 Max. transient thermal impedance

$$Z_{\rm thJC}$$
=f $(t_{\rm p})$ 

parameter:  $D=t_p/T$ 

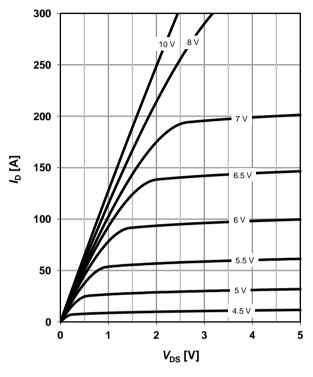




## 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$ 

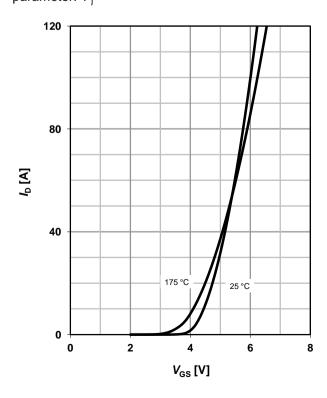
parameter: V<sub>GS</sub>



## 7 Typ. transfer characteristics

 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 

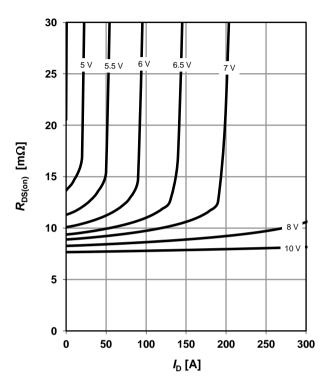
parameter:  $T_{\rm j}$ 



#### 6 Typ. drain-source on resistance

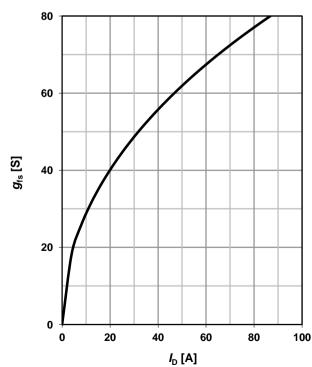
 $R_{DS(on)}=f(I_D); T_j=25 \text{ °C}$ 

parameter: V<sub>GS</sub>



## 8 Typ. forward transconductance

 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C





## 9 Drain-source on-state resistance

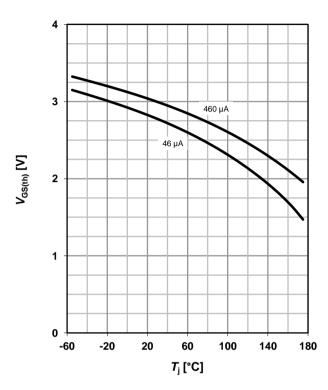
 $R_{DS(on)} = f(T_i); I_D = 46 \text{ A}; V_{GS} = 10 \text{ V}$ 

# 25 20 $R_{\mathrm{DS(on)}}$ [m $\Omega$ ] 15 10 typ 5 0 -60 -20 20 60 100 140 180 *T*<sub>j</sub> [°C]

## 10 Typ. gate threshold voltage

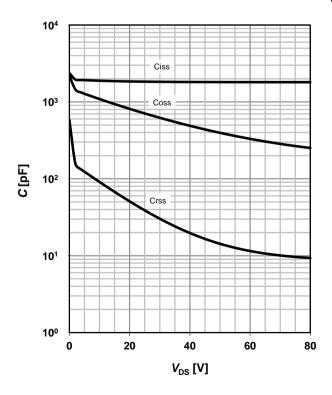
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>



## 11 Typ. capacitances

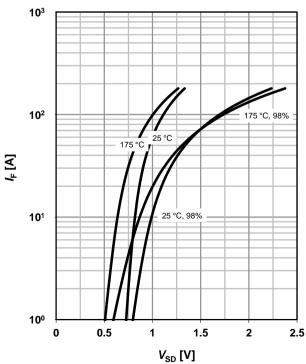
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 



#### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter: T<sub>i</sub>

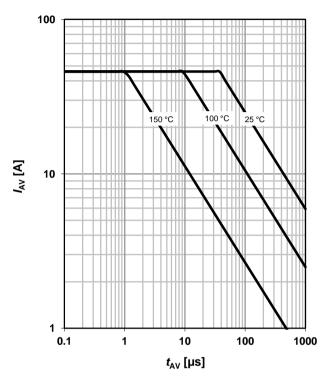




#### 13 Avalanche characteristics

 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

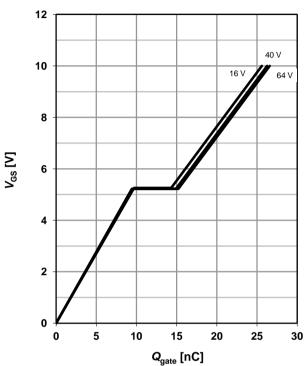
parameter:  $T_{j(start)}$ 



#### 14 Typ. gate charge

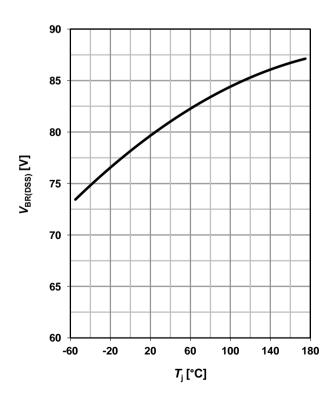
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =46 A pulsed

parameter:  $V_{\rm DD}$ 

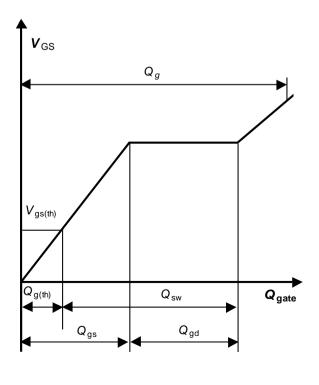


#### 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$ 

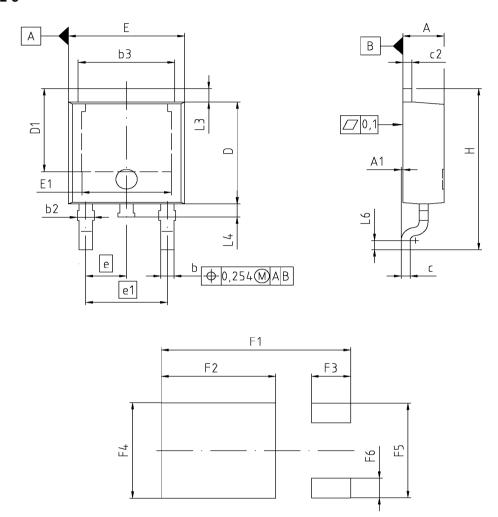


#### 16 Gate charge waveforms





## PG-TO252-3



DIM	MILLIN	MILLIMETERS		HES	
DIM	MIN	MAX	MIN	MAX	
Α	2.159	2.413	0.085	0.095	
A1	0.000	0.150	0.000	0.006	
b	0.635	0.889	0.025	0.035	
b2	0.650	1.150	0.026	0.045	
b3	5.004	5.500	0.197	0.217	
С	0.457	0.580	0.018	0.023	
c2	0.460	0.980	0.018	0.039	
D	5.969	6.223	0.235	0.245	
D1	5.020	5.842	0.198	0.230	
Е	6.400	6.731	0.252	0.265	
E1	4.850	5.207	0.191	0.205	
е	2.	286	0.090		
e1	4.	4.572		180	
N		3		3	
Н	9.400	10.480	0.370	0.413	
L3	0.900	1.143	0.035	0.045	
L4	0.584	0.950	0.023	0.037	
L6	0.510	0.686	0.020	0.027	
F1	10.500	10.700	0.413	0.421	
F2	6.300	6.500	0.248	0.256	
F3	2.100	2.300	0.083	0.091	
F4	5.700	5.900	0.224	0.232	
F5	5.660	5.860	0.222	0.231	
F6	1.100	1.300	0.043	0.051	

REFERENCE JEDEC TO252
SCALE 0
2.0 = 0 0 2.0 4mm
EUROPEAN PROJECTION
<b>ISSUE DATE</b> 21-09-2005
FILE TO252_1



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